### 10784510 CLS

Most Frequently Occurring Classifications of Patents Returned From A Search of 10784510 on September 02, 2004

### 6 250/492.21 3 250/309 2 250/252.1 2 250/281 2 250/283 2 250/492.3 2 359/484 Cross-Reference Classifications 12 250/397 9 250/398 5 250/492.3 3 250/281 3 250/282 3 250/288 3 250/492.2 3 315/111.81 2 118/715 2 250/2512 250/298 2 250/423R 2 250/443.1 2 313/361.1 2 313/363.1 2 359/324 Combined Classifications 14 250/492.2 13 250/397 9 250/398 7 250/492.3 6 250/492.21 5 250/281 4 250/288 3 250/251 3 250/282 3 250/283 3 250/309 3 250/423R 3 315/111.81 2 118/715 2 250/252.1

Original Classifications

11 250/492.2

## 10784510\_CLS

- 2 250/298
- 250/443.1
- 313/361.1 313/363.1 324/71.3 359/324
- 2 2 2 2 2 2 2

- 359/484 378/160 427/523

### 10784510 CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returne

From A Search of 10784510 on September 02, 2004

(11 OR, 3 XR) 14 250/492.2

Class 250: RADIANT ENERGY

250/492.1 IRRADIATION OF OBJECTS OR MATERIAL 250/492.2 .Irradiation of semiconductor devices

(1 OR, 12 XR) 13 250/397

Class 250: RADIANT ENERGY

WITH CHARGED PARTICLE BEAM DEFLECTION OR 250/396R

FOCUSSING

250/397 .With detector

(0 OR, 9 XR) 9 250/398

Class 250: RADIANT ENERGY

250/396R WITH CHARGED PARTICLE BEAM DEFLECTION OR

FOCUSSING

250/398 .With target means

7 250/492.3 (2 OR, 5 XR)

Class 250: RADIANT ENERGY

250/492.1 IRRADIATION OF OBJECTS OR MATERIAL 250/492.3 .Ion or electron beam irradiation

6 250/492.21 (6 OR, 0 XR) Class 250: RADIANT ENERGY

250/281 (2 OR, 3 XR)

Class 250: RADIANT ENERGY

250/281 IONIC SEPARATION OR ANALYSIS

4 250/288 (1 OR, 3 XR)

Class 250: RADIANT ENERGY

IONIC SEPARATION OR ANALYSIS 250/281

250/288 .With sample supply means

3 250/251 (1 OR, 2 XR)

Class 250: RADIANT ENERGY

250/251 ELECTRICALLY NEUTRAL MOLECULAR OR ATOMIC BEAM

DEVICES AND METHODS

3 250/282 (0 OR, 3 XR)

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Class 250: RADIANT ENERGY

250/281 IONIC SEPARATION OR ANALYSIS

250/282 .Methods

3 250/283 (2 OR, 1 XR)

Class 250: RADIANT ENERGY

IONIC SEPARATION OR ANALYSIS 250/281

250/282 .Methods

250/283 ..With collection of ions

3 250/309 (3 OR, 0 XR)

Class 250: RADIANT ENERGY

250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED

PARTICLES

250/309 .Positive ion probe or microscope type

3 250/423R (1 OR, 2 XR)

> Class 250: RADIANT ENERGY 250/423R ION GENERATION

3 315/111.81 (0 OR, 3 XR)

Class 315: ELECTRIC LAMP AND DISCHARGE DEVICES: SYSTEMS

315/111.01 DISCHARGE DEVICE LOAD WITH FLUENT MATERIAL

SUPPLY TO THE DISCHARGE SPACE

315/111.81 .Electron or ion source

2 118/715 (0 OR, 2 XR)

Class 118 : COATING APPARATUS

118/715 GAS OR VAPOR DEPOSITION

250/252.1 (2 OR, 0 XR)

Class 250: RADIANT ENERGY

250/252.1 CALIBRATION OR STANDARDIZATION METHODS

(0 OR, 2 XR) 2 250/298

Class 250: RADIANT ENERGY

250/281 IONIC SEPARATION OR ANALYSIS

250/294 .Static field-type ion path-bending selecting

means

.. Magnetic field path-bending means

2 250/443.1 (0 OR, 2 XR)

Class 250: RADIANT ENERGY

INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED 250/306

PARTICLES

250/440.11 .Analyte supports 250/443.1 ..With heat transfer or temperature-indication

# 10784510\_CLSTITLES means

2	313/359.1	OR, 2 XR) : ELECTRIC LAMP AND DISCHARGE DEVICES WITH POSITIVE OR NEGATIVE ION ACCELERATION .Means for deflecting or focusing
2	313/359.1	OR, 2 XR) : ELECTRIC LAMP AND DISCHARGE DEVICES WITH POSITIVE OR NEGATIVE ION ACCELERATION .Extraction or target electrode
2 G		OR, 1 XR) : ELECTRICITY: MEASURING AND TESTING DETERMINING NONELECTRIC PROPERTIES BY MEASURIN
G	324/71.3	ELECTRIC PROPERTIES Beam of atomic particles
2	359/237	OR, 2 XR) : OPTICS: SYSTEMS OPTICAL MODULATOR .Having particular chemical composition or structureMagneto-optic crystal material
2	359/483	OR, 0 XR) : OPTICS: SYSTEMS POLARIZATION WITHOUT MODULATION .Time invariant electric, magnetic, or electromagnetic field responsive (e.g., ele
ctro-optical,		
		magneto-optical)
2		OR, 1 XR) : X-RAY OR GAMMA RAY SYSTEMS OR DEVICES BEAM CONTROL .Shutter or chopper
2		OR, 1 XR) : COATING PROCESSES DIRECT APPLICATION OF ELECTRICAL, MAGNETIC, WAVE, OR PARTICULATE ENERGY .Ion plating or implantation